

Séminaires du C2RMF

Vendredi 6 septembre 2019

Amphithéâtre Palissy, 11h00

CENTRE DE
RECHERCHE
ET DE
RESTAURATION
DES MUSÉES
DE FRANCE

TEASING OUT THE HIDDEN LAYERS OF AN OLD MASTER PAINTING USING TERAHERTZ IMAGING

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Terahertz imaging permits the quantitative nondestructive characterization of a range of art and archaeological objects in three dimensions.

In this talk, I focus on our work measuring the thicknesses of various preparatory paint layers in the 17th century oil painting on canvas Madonna in Preghiera by Giovanni Battista Salvi da Sassoferrato (Musée de la Cour d'Or, Metz Métropole, Inventory number 11621). The ability to measure thin layers (down to ~10 microns) depends crucially on advanced signal processing--not simply the direct physical measurement. I also discuss our work based on terahertz techniques to characterize other objects, including the thickness of the slip on a Gallo-Roman amphora sherd and to read an inscription through an obscuring lead oxide layer on a lead funerary cross dating from 1092.

